

Notice of References Cited	Application/Control No. 09/590,897	Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL.	
	Examiner JAMES M. MITCHELL	Art Unit 2813	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,276,289	01-1994	Satoh et al.	174/260
*	C	US-4,730,665	03-1988	Cutchaw, John M.	165/80.4
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*	E	US-5,157,588	10-1992	Kim et al.	361/736
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IBM Technical disclosure, "Module Probe Package", 5/1991, Vol. 33 Issue 12 pages 85-86
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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